

- Submission
- VI. Program Planning
- Proposed Change to 2008 Briefing Schedule
  - 2010 Program Planning Proposals
  - Briefing Report on Voter Fraud and Voter Intimidation
  - Briefing Report on Racial Categorization in the Census
  - Briefing Report on the Educational Effectiveness of Historically Black Colleges and Universities
- VII. State Advisory Committee Issues
- Florida SAC
  - Kentucky SAC
  - Wyoming SAC
  - Appointment to Texas SAC
- VIII. Future Agenda Items
- IX. Adjourn

**FOR FURTHER INFORMATION CONTACT:**  
Lenore Ostrowsky, Acting Chief, Public Affairs Unit (202) 376-8582.

Dated: April 29, 2008.

**David Blackwood,**

*General Counsel.*

[FR Doc. 08-1207 Filed 4-29-08; 1:57pm]

**BILLING CODE 6335-01-P**

## DEPARTMENT OF COMMERCE

### Industry and Security Bureau

#### Materials Technical Advisory Committee; Notice of Partially Closed Meeting

The Materials Technical Advisory Committee will meet on May 15, 2008, 10 a.m., Herbert C. Hoover Building, Room 3884, 14th Street between Constitution & Pennsylvania Avenues, NW., Washington, DC. The Committee advises the Office of the Assistant Secretary for Export Administration with respect to technical questions that affect the level of export controls applicable to materials and related technology.

#### Agenda

##### Public Session

1. Opening Remarks and Introduction.
2. Report of Composite Working Group and Chemical Equipment Subgroup.
  - a. CWG General Technology Note white paper.
  - b. Wassenaar non-paper on 1C010.
3. Report of Eric McClafferty on response received from the chemical processing equipment representatives regarding the ECCN review process.
4. Update on webinars, export training modules on BIS webpage.
5. Public comments from teleconference and physical attendees.
6. Any other business.

#### Closed Session

7. Discussion of matters determined to be exempt from the provisions relating to public meetings found in 5 U.S.C. app. 2 sections 10(a)(1) and 10(a)(3).

The open session will be accessible via teleconference to 20 participants on a first come, first serve basis. To join the conference, submit inquiries to Ms. Yvette Springer at [Yspringer@bis.doc.gov](mailto:Yspringer@bis.doc.gov) no later than May 8, 2008.

A limited number of seats will be available during the public session of the meeting. Reservations are not accepted. To the extent time permits, members of the public may present oral statements to the Committee. Written statements may be submitted at any time before or after the meeting. However, to facilitate distribution of public presentation materials to Committee members, the materials should be forwarded prior to the meeting to Ms. Springer via e-mail.

The Assistant Secretary for Administration, with the concurrence of the delegate of the General Counsel, formally determined on April 25, 2008, pursuant to Section 10(d) of the Federal Advisory Committee Act, as amended, that the portion of the meeting dealing with matters the premature disclosure of which would likely frustrate the implementation of a proposed agency action as described in 5 U.S.C. 552b(c)(9)(B) shall be exempt from the provisions relating to public meetings found in 5 U.S.C. app. 2 sections 10(a)(1) and 10(a)(3). The remaining portions of the meeting will be open to the public.

For more information, call Yvette Springer at (202) 482-2813.

Dated: April 28, 2008.

**Yvette Springer,**

*Committee Liaison Officer.*

[FR Doc. E8-9587 Filed 4-30-08; 8:45 am]

**BILLING CODE 3510-JT-P**

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### Rice University, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 2104, U.S. Department of Commerce,

14th and Constitution Ave, NW., Washington, DC.

*Comments:* None received. *Decision:* Approved. We know of no instruments of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, that was being manufactured in the United States at the time of its order.

*Docket Number:* 08-008. *Applicant:* Rice University, Houston, TX 77005. *Instrument:* Low Temperature Microscopy Scanning Probe. *Manufacturer:* Nano Magnetics Instruments, Ltd., Turkey. *Intended Use:* See notice at 73 FR 18258, April 3, 2008. *Reasons:* This instrument can supply 300mK scanning Hall probe microscopy with 50 NM special resolution, which is essential to the intended use.

*Docket Number:* 08-009. *Applicant:* University of Michigan, Department of Materials Science and Engineering, 2300 Hayward St., Ann Arbor, MI 48109-2136. *Instrument:* Heating Microscope Optical Dilatometer. *Manufacturer:* Expert System Solutions, Italy. *Intended Use:* See notice at 73 FR 18258, April 3, 2008. *Reasons:* This instrument can be used for sintering shrinkage up to 1600 degrees centigrade, thermal expansion down to room temperature and cristobalite transformation at 215 degrees centigrade. An essential feature of the equipment is that it performs a non-contact optical measurement.

April 24, 2008.

**Faye Robinson,**

*Director, Statutory Import Programs Staff, Import Administration.*

[FR Doc. E8-9445 Filed 4-30-08; 8:45 am]

**BILLING CODE 3510-DS-M**

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### University of Southern California; Notice of Decision on Application for Duty-Free Entry of Electron Microscope

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 2104, U.S. Department of Commerce, 14th and Constitution Avenue, NW., Washington, DC.

*Docket Number:* 08-007. *Applicant:* University of Southern California, Los Angeles, CA 90089-9045. *Instrument:* Transmission Electron Microscope, Model JEM-2100. *Manufacturer:* Jeol,